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IEEE International Conference on Microelectronic Test Structures IEEE Electron Devices Society

CMP: Biography TS 1996. 1996 IEEE INTERNATIONAL CONFERENCE. ON MICROELECTRONIC TEST STRUCTURES. March 25-28, 1996. Trento, Italy. PROCEEDINGS. ICMTS 1996, 1996 International Conference on Microelectronic Test. Pubblicazioni - Università degli Studi di Salerno Publications of Luca Selmi Papers on International Journals. - diegm Jun 11, 2015. Proceedings of the Mediterranean Electrotechnical Conference - MELECON 01/2012 DOI: 10.1109/MELCON.2012.6196410. ABSTRACT. Patents ICMTS 1996 IEEE International Conference on Microelectronic Test Structures, March 25-28, 1996, Trento, Italy. Publisher: IEEE. Publish date: 1996. Document Curriculum Vitae - Lirimm In: ICMTS 1996 IEEE International Conference on Microelectronic Test Structures Trento, Italy March 25-28, 1996 Piscataway Institute of Electrical & Electronics . 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